

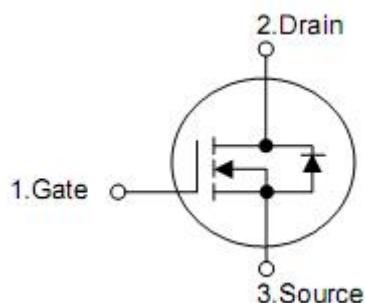
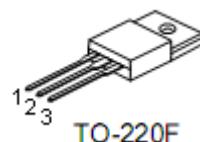
## 1. Description

The KIA10N65H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

## 2. Features

- $R_{DS(on)}=0.65\Omega$  @  $V_{GS}=10V$
- Low gate charge ( typical 48nC)
- Fast switching capability
- avalanche energy specified
- Improved dv/dt capability

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source

## 4. Absolute maximum ratings

( $T_C = 25^\circ\text{C}$ , unless otherwise specified)

Parameter	Symbol	Rating	Units
Drain-source voltage	$V_{DSS}$	650	V
Gate-source voltage	$V_{GSS}$	+30	V
Drain current continuous	$I_D$	10.0*	A
		6.0*	A
Drain current pulsed (note1)	$I_{DP}$	40.0*	A
Avalanche energy	Repetitive (note1)	$E_{AR}$	mJ
	Single pulse (note2)	$E_{AS}$	mJ
Peak diode recovery dv/dt (note3)	dv/dt	4.5	V/ns
Total power dissipation	$P_D$	52	W
		0.42	W/ $^\circ\text{C}$
Junction temperature	$T_J$	+150	$^\circ\text{C}$
Storage temperature	$T_{STG}$	-55~+150	$^\circ\text{C}$

\* Drain current limited by maximum junction temperature.

## 5. Thermal characteristics

Parameter	Symbol	Rating	Unit
Thermal resistance, Junction-ambient	$R_{thJA}$	62.5	$^\circ\text{C}/\text{W}$
Thermal resistance, case-to-sink typ.	$R_{thCS}$	-	$^\circ\text{C}/\text{W}$
Thermal resistance, Junction-case	$R_{thJC}$	2.4	$^\circ\text{C}/\text{W}$

## 6. Electrical characteristics

( $T_J=25^\circ\text{C}$ , unless otherwise notes)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Off characteristics						
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	650	-	-	V
Zero gate voltage drain current	$I_{\text{DSS}}$	$V_{\text{DS}}=650\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{\text{DS}}=480\text{V}, T_c=125^\circ\text{C}$	-	-	10	$\mu\text{A}$
Gate-body leakage current	$I_{\text{GSS}}$	$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA
		$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-100	nA
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_{\text{D}}=250\mu\text{A}$	-	0.7	-	V/ $^\circ\text{C}$
On characteristics						
Gate threshold voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Static drain-source on-resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=5.0\text{A}$	-	0.65	0.75	$\Omega$
Dynamic characteristics						
Input capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	1650	-	pF
Output capacitance	$C_{\text{oss}}$		-	1665	-	pF
Reverse transfer capacitance	$C_{\text{rss}}$		-	18	-	pF
Switching characteristics						
Turn-on delay time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=325\text{V}, I_{\text{D}}=10.0\text{A}, R_{\text{G}}=25\Omega$ (note4,5)	-	25	-	ns
Rise time	$t_r$		-	70	-	ns
Turn-off delay time	$t_{\text{d}(\text{off})}$		-	140	-	ns
Fall time	$t_f$		-	80	-	ns
Total gate charge	$Q_g$	$V_{\text{DS}}=520\text{V}, I_{\text{D}}=10.0\text{A}, V_{\text{GS}}=10\text{V}$ (note4,5)	-	48	-	nC
Gate-source charge	$Q_{\text{gs}}$		-	7.0	-	nC
Gate-drain charge	$Q_{\text{gd}}$		-	18.0	-	nC
Drain-source diode characteristics						
Drain-source diode forward voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=10.0\text{A}$	-	-	1.4	V
Continuous drain-source current	$I_{\text{SD}}$		-	-	10.0	A
Pulsed drain-source current	$I_{\text{SM}}$		-	-	40.0	A
Reverse recovery time	$t_{\text{rr}}$	$I_{\text{SD}}=10.0\text{A}$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note4)	-	430	-	ns
Reverse recovery charge	$Q_{\text{rr}}$		-	4.3	-	$\mu\text{C}$

Note: 1. repetitive rating:pulse width limited by maximum junction temperature

2.  $L=13\text{mH}, I_{\text{AS}}=10.0\text{A}, V_{\text{DD}}=50\text{V}, R_{\text{G}}=25\Omega$ , staring  $T_J=25^\circ\text{C}$

3.  $I_{\text{SD}} \leq 10.0, dI/dt \leq 200\text{A}/\mu\text{s}, V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$ , staring  $T_J=25^\circ\text{C}$

4. Pulse test:pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$

5. Essentially independent of operating temperature

## 7. Test circuits and waveforms

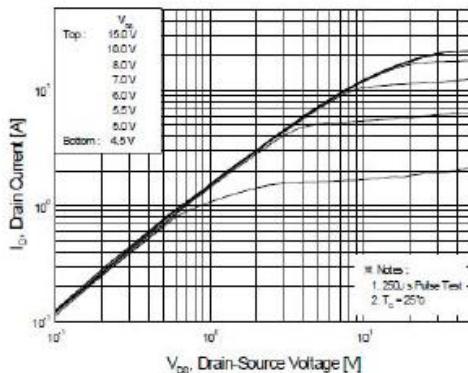


Figure 1. On-Region Characteristics

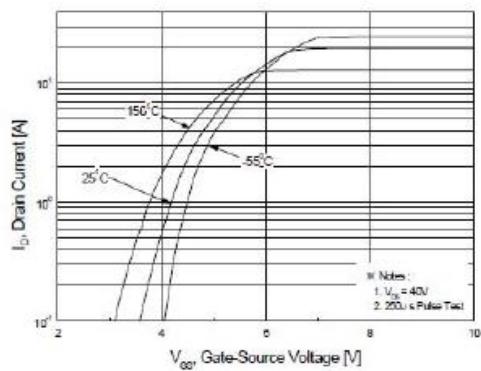


Figure 2. Transfer Characteristics

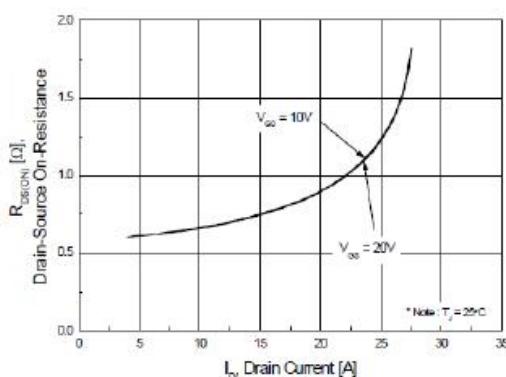


Figure 3. On-Resistance Variation vs  
Drain Current and Gate Voltage

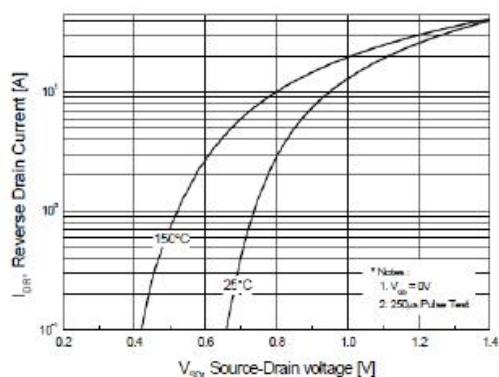


Figure 4. Body Diode Forward Voltage  
Variation with Source Current  
and Temperature

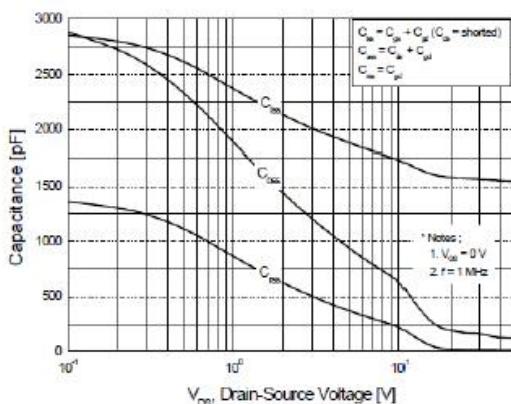


Figure 5. Capacitance Characteristics

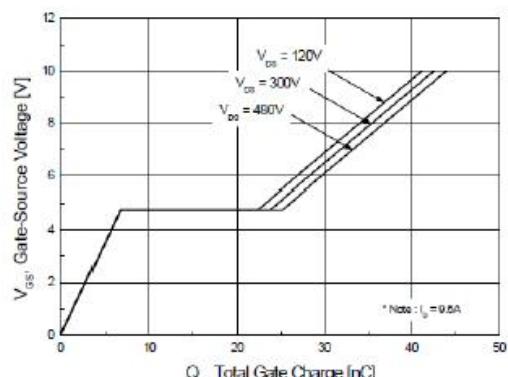
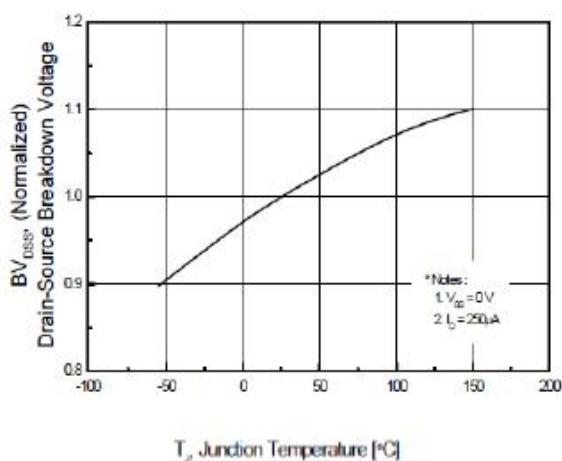
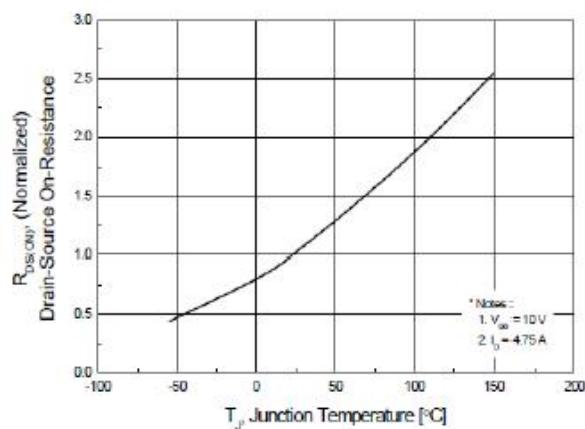


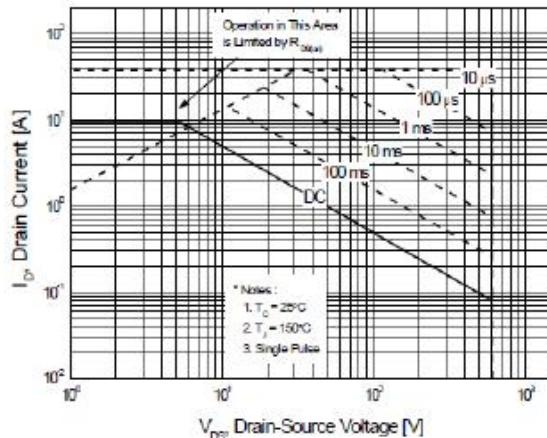
Figure 6. Gate Charge Characteristics



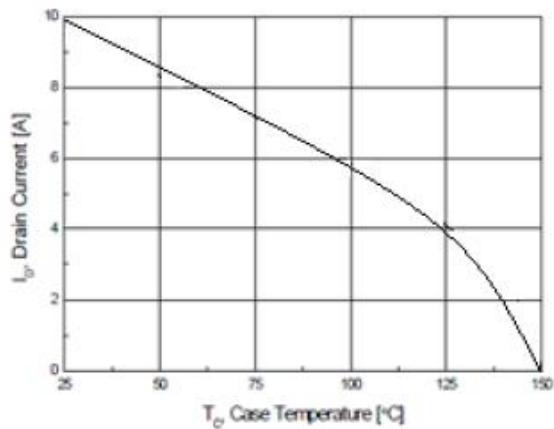
**Figure 7. Breakdown Voltage Variation  
vs Temperature**



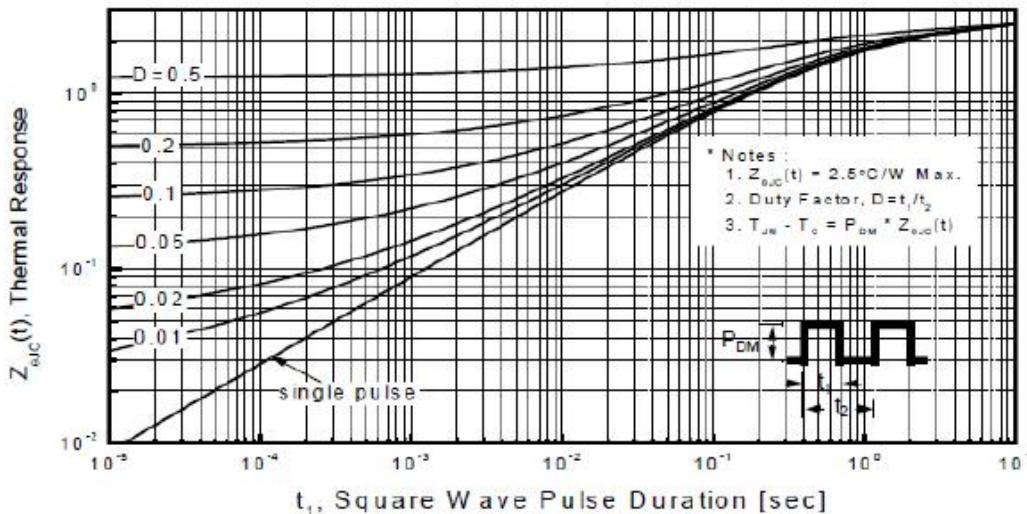
**Figure 8. On-Resistance Variation  
vs Temperature**



**Figure 9. Maximum Safe Operating Area**



**Figure 10. Maximum Drain Current  
vs Case Temperature**



**Figure 11. Transient Thermal Response Curve for TO220F**